



1 / 23

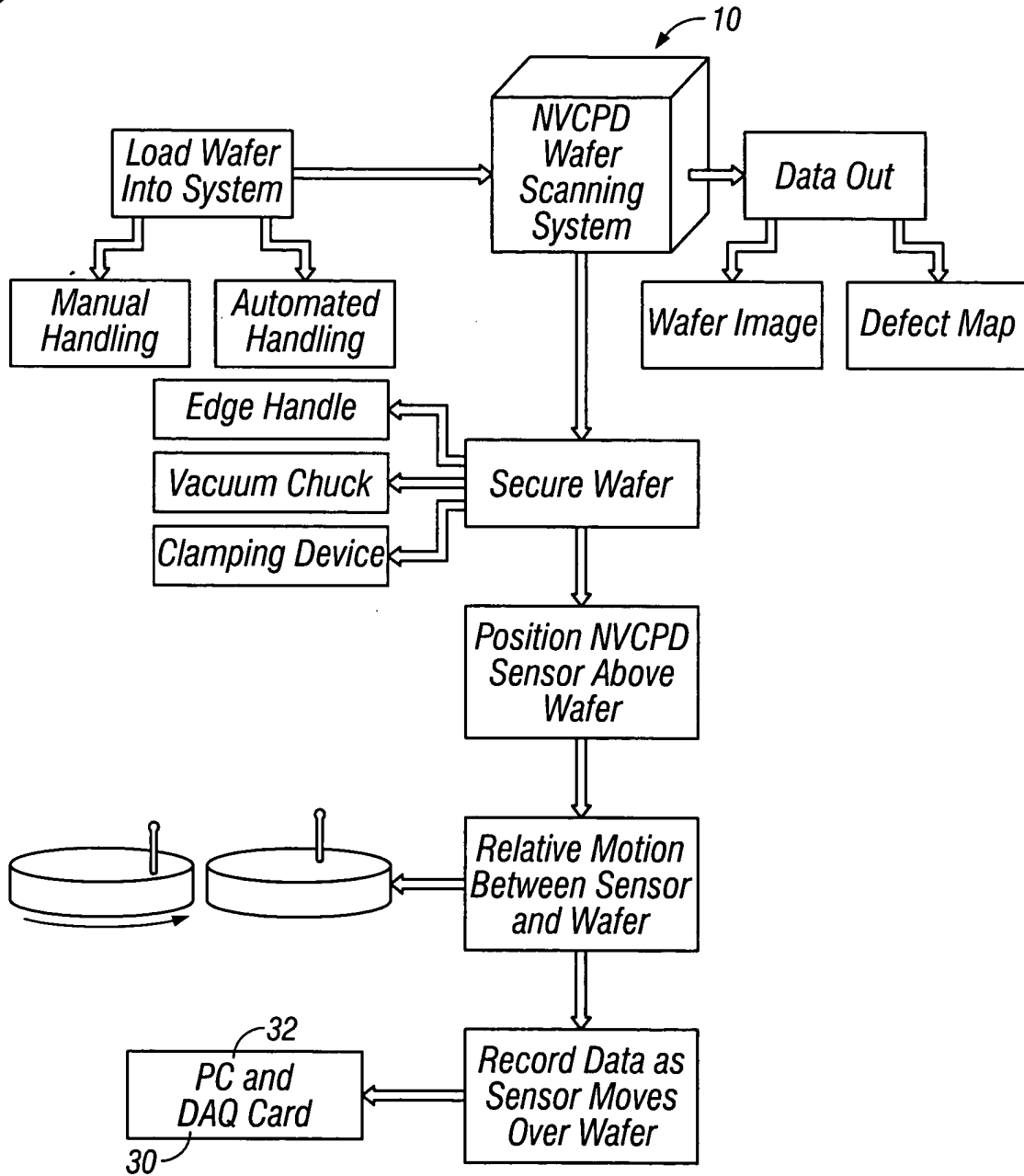


FIG. 1

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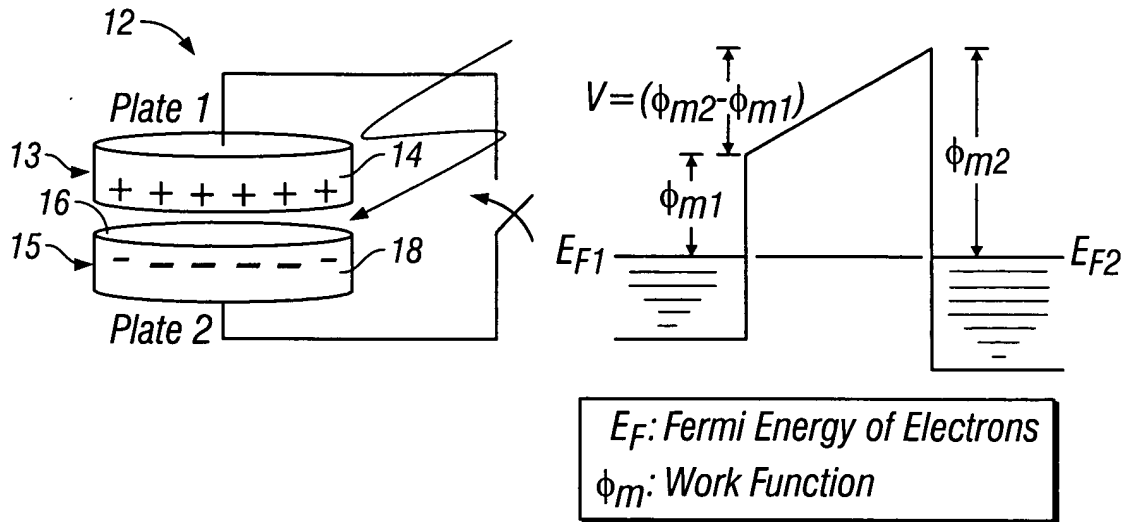


FIG. 2

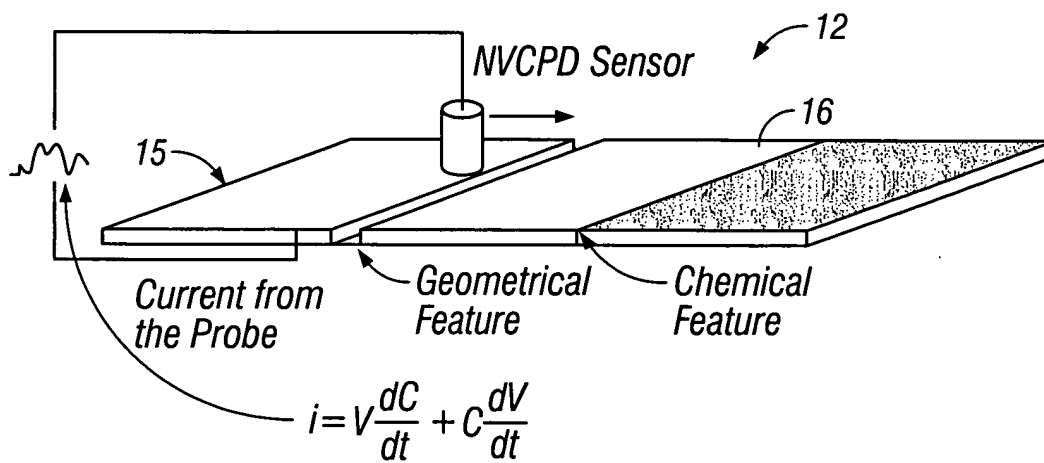


FIG. 3

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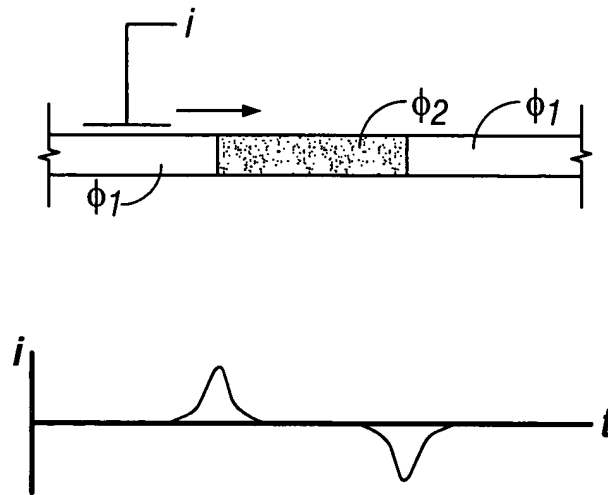


FIG. 4

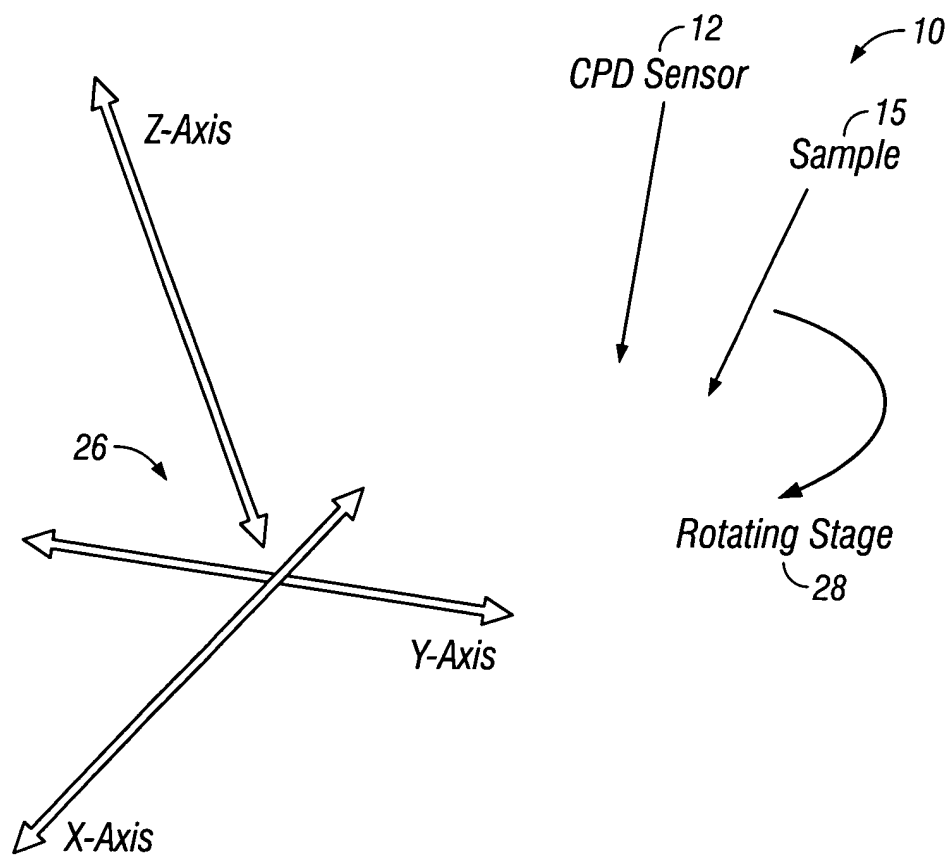


FIG. 5

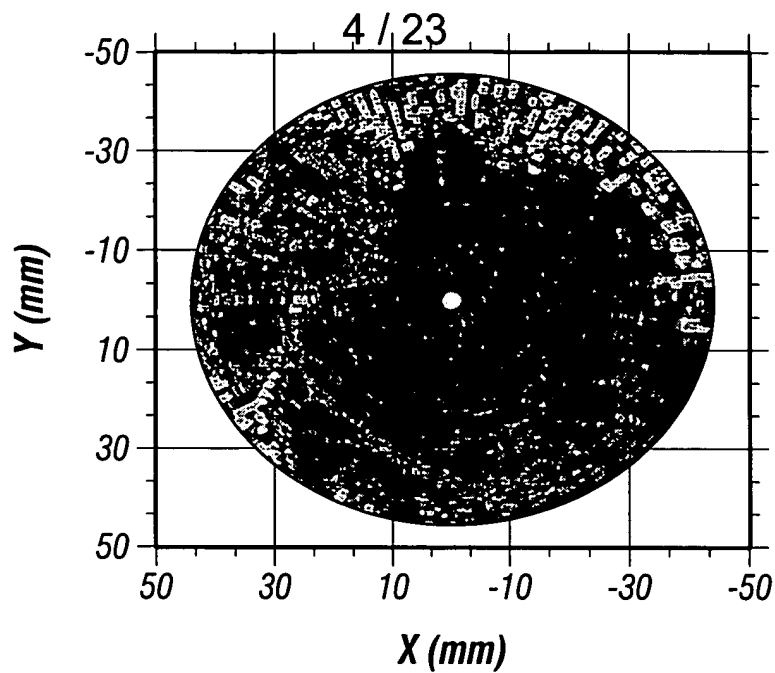


FIG. 6

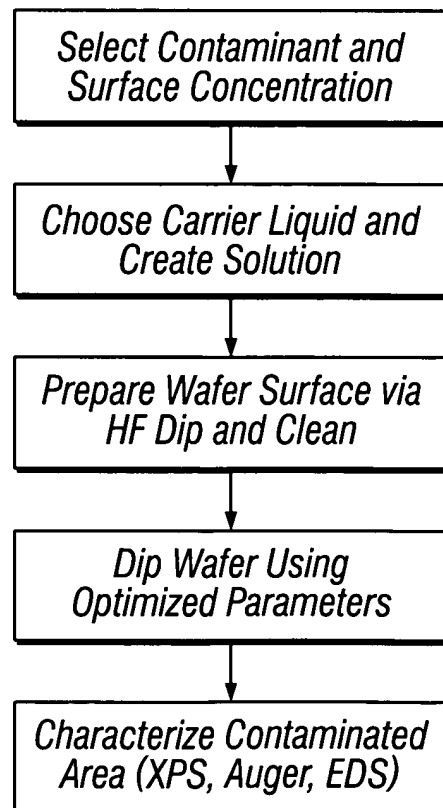


FIG. 7

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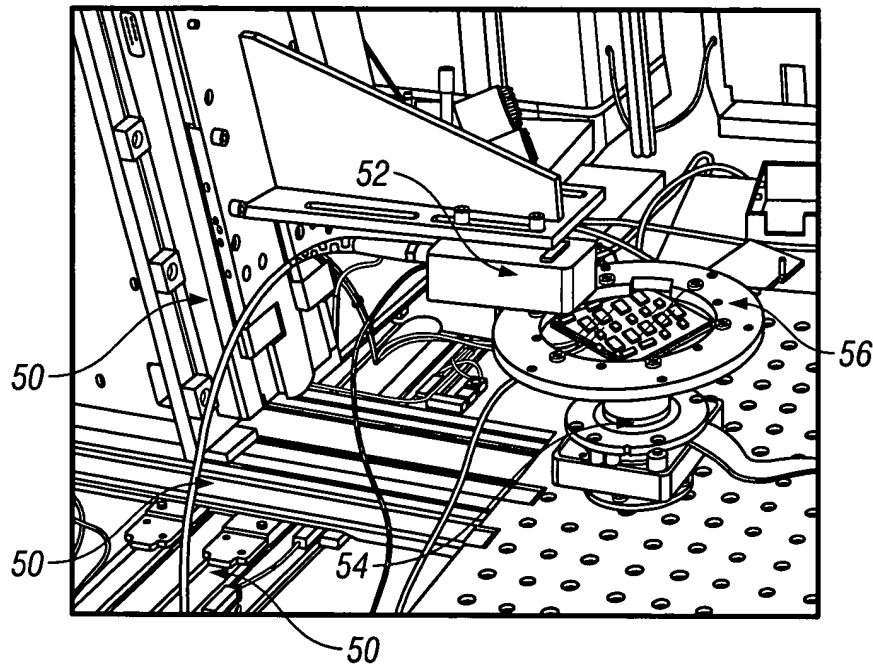


FIG. 8A

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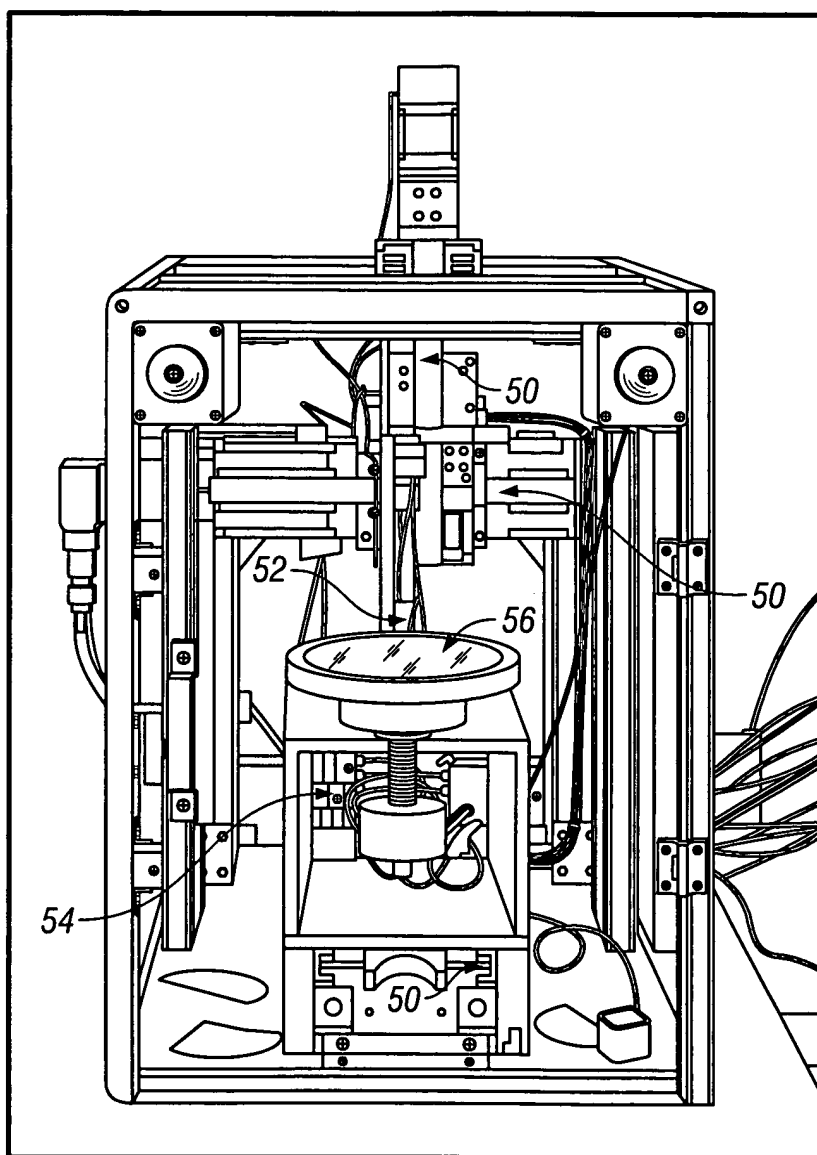


FIG. 8B

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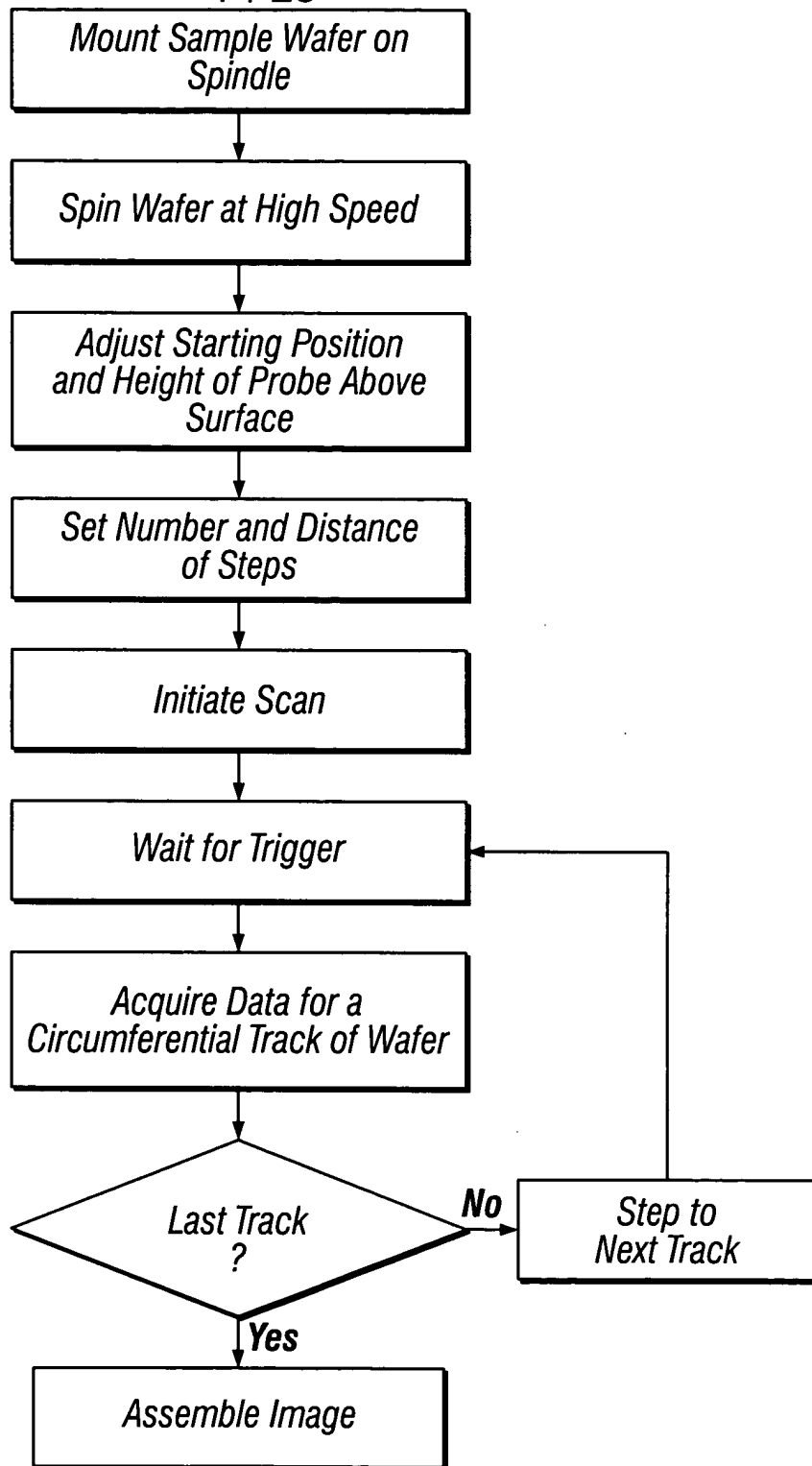


FIG. 9

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

Appl. No.: 10/771,628

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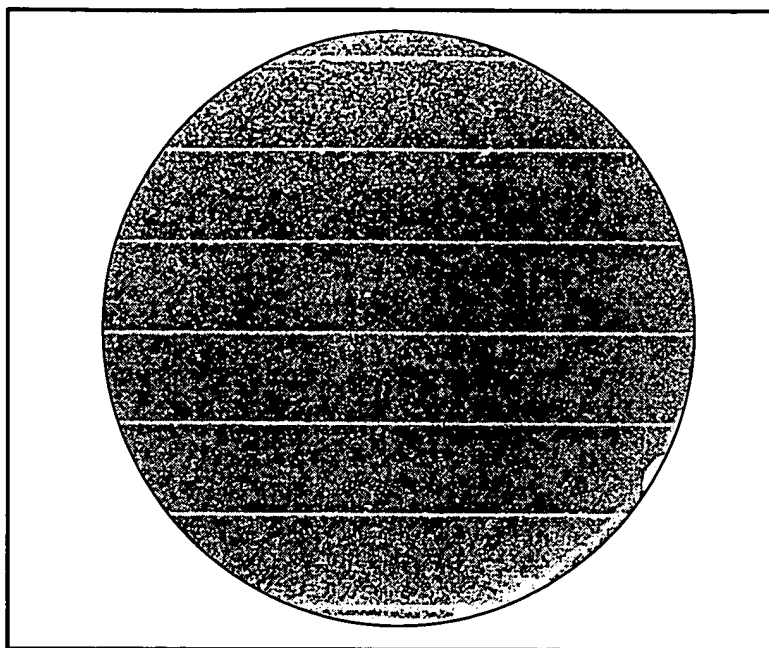


FIG. 10A

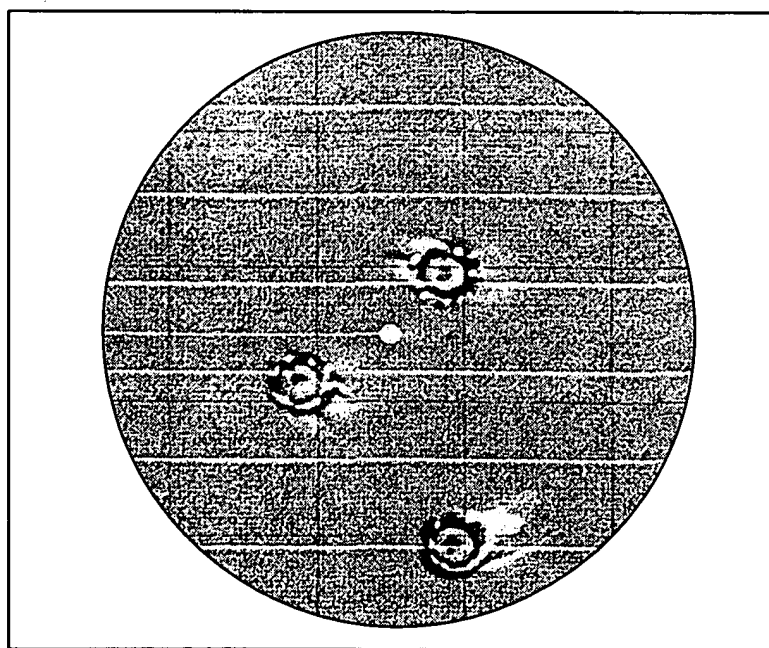


FIG. 10B

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

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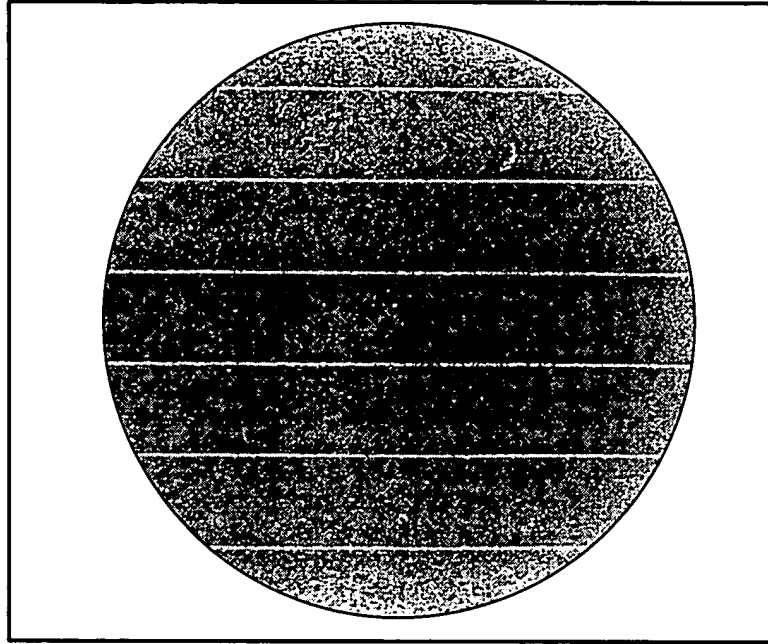


FIG. 11A

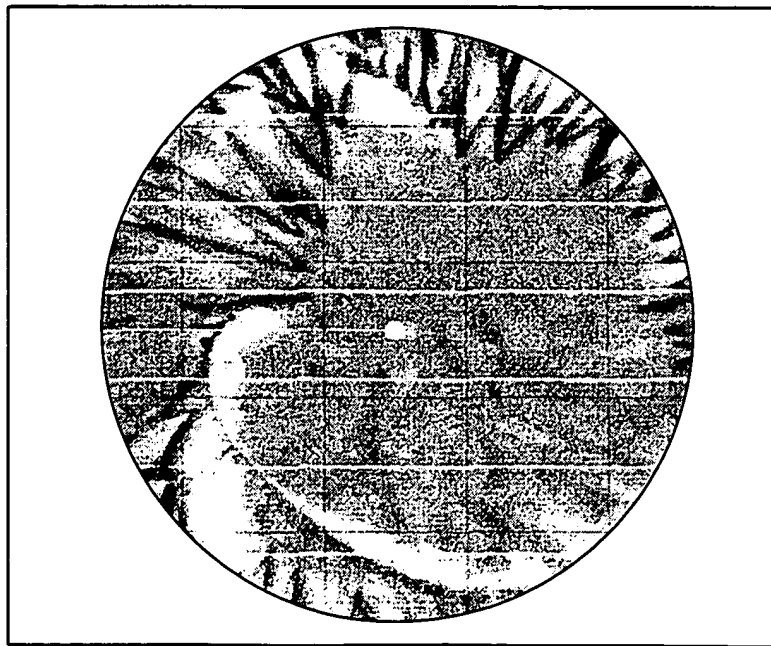


FIG. 11B

Title: WAFER INSPECTION SYSTEM

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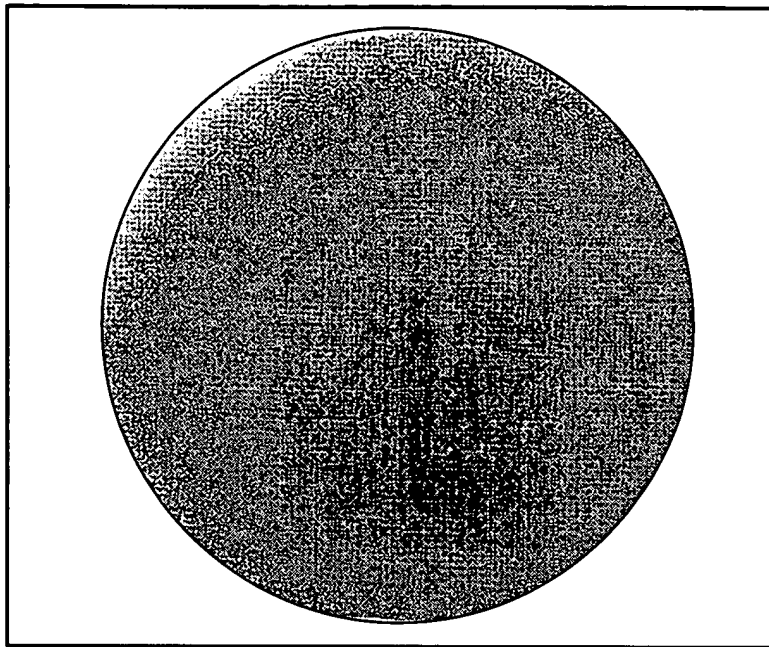


FIG. 12A

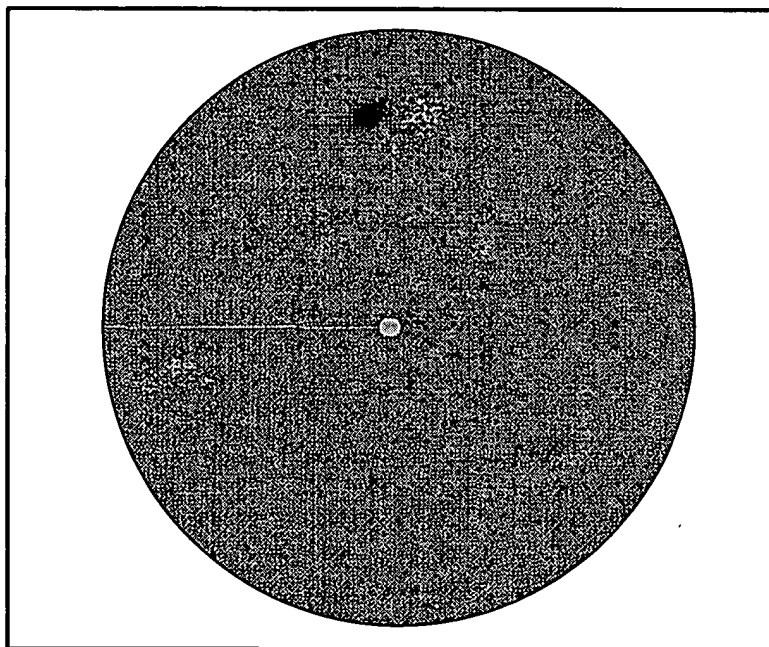


FIG. 12B

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

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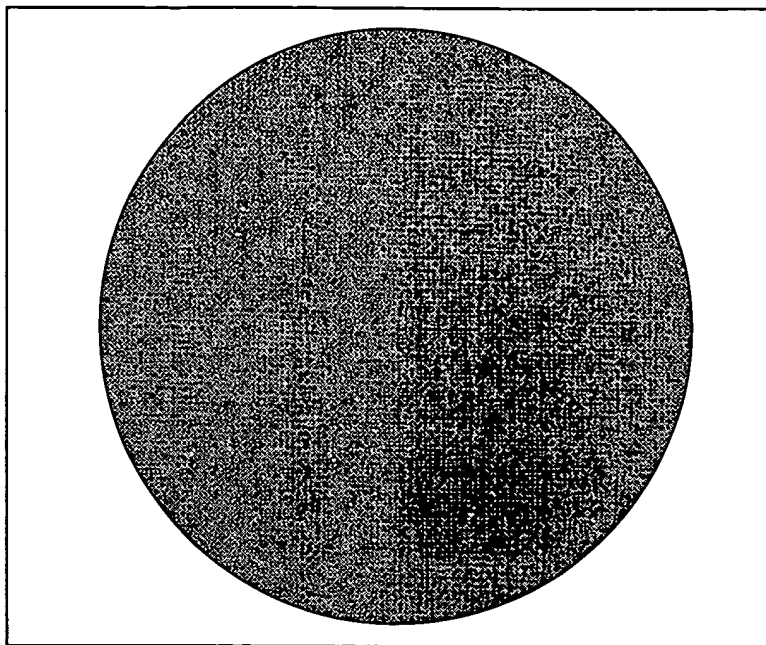


FIG. 13A

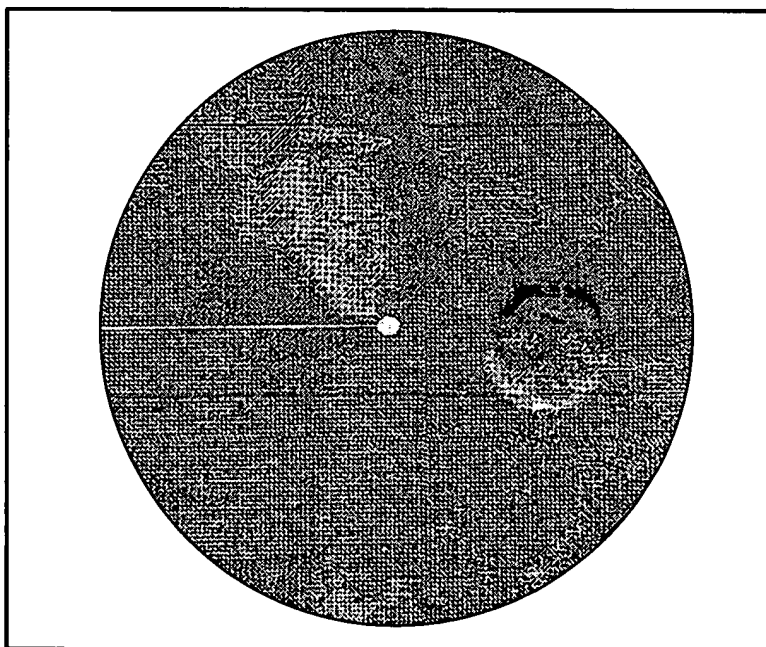


FIG. 13B

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

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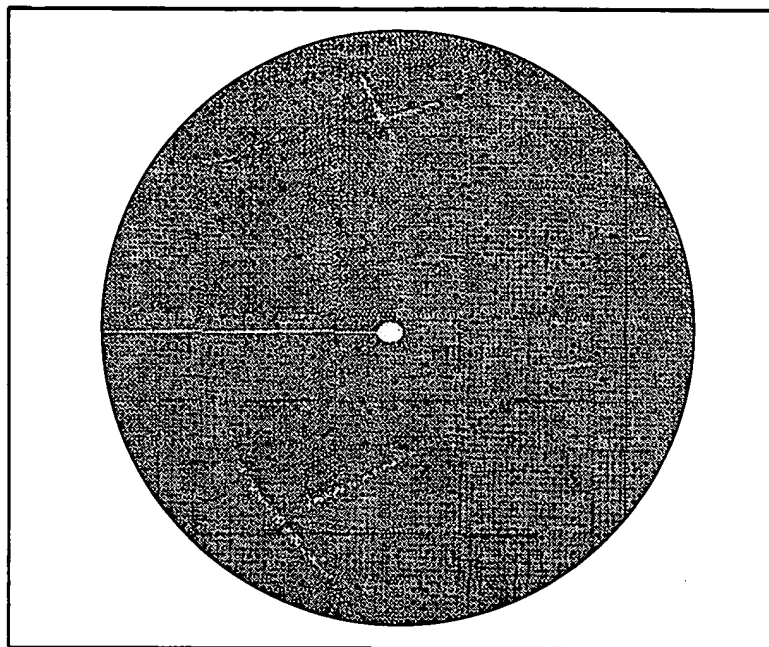


FIG. 14

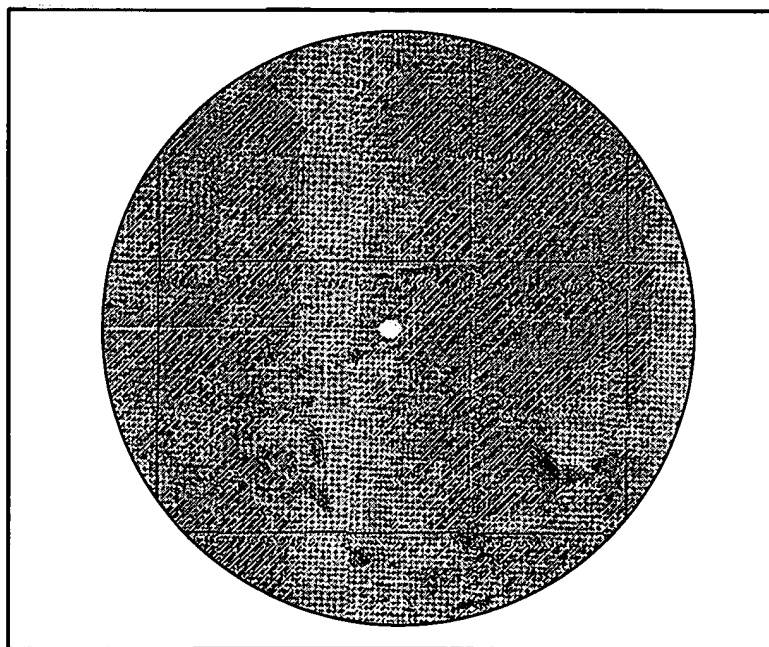


FIG. 15

Title: WAFER INSPECTION SYSTEM

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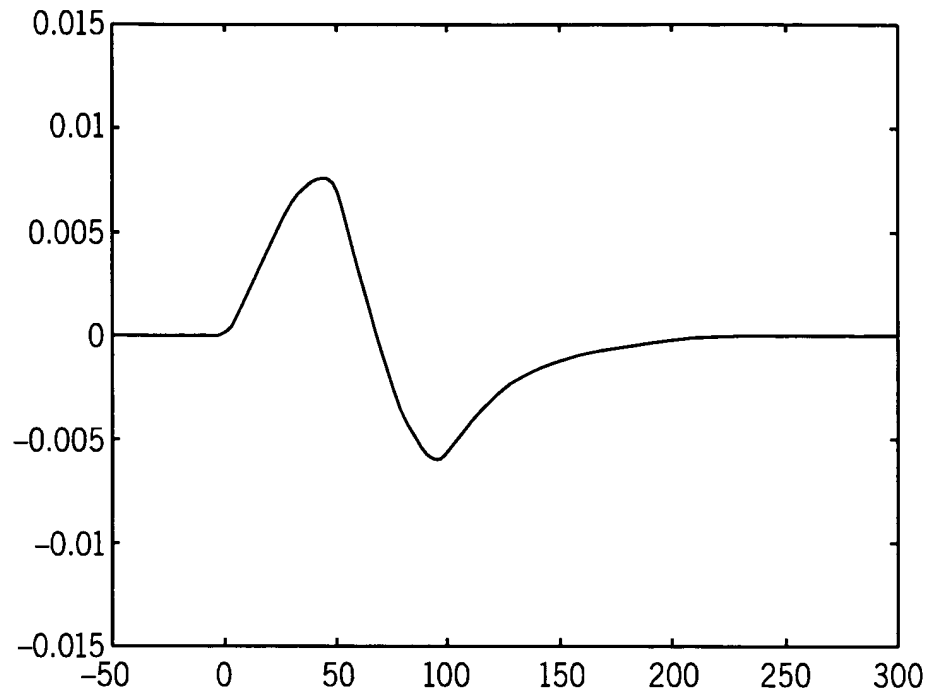


FIG. 16

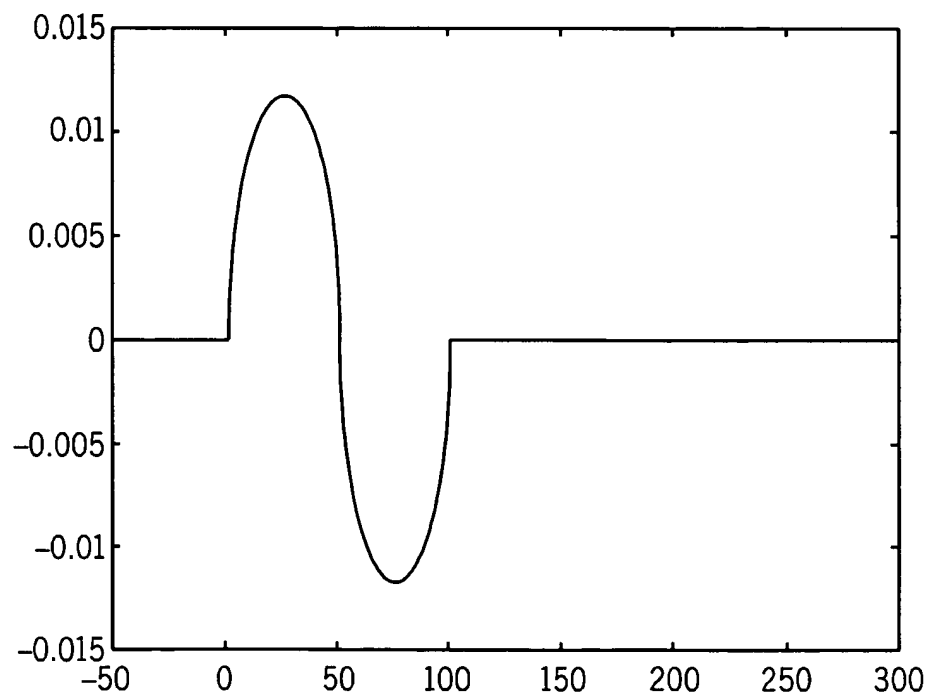


FIG. 17

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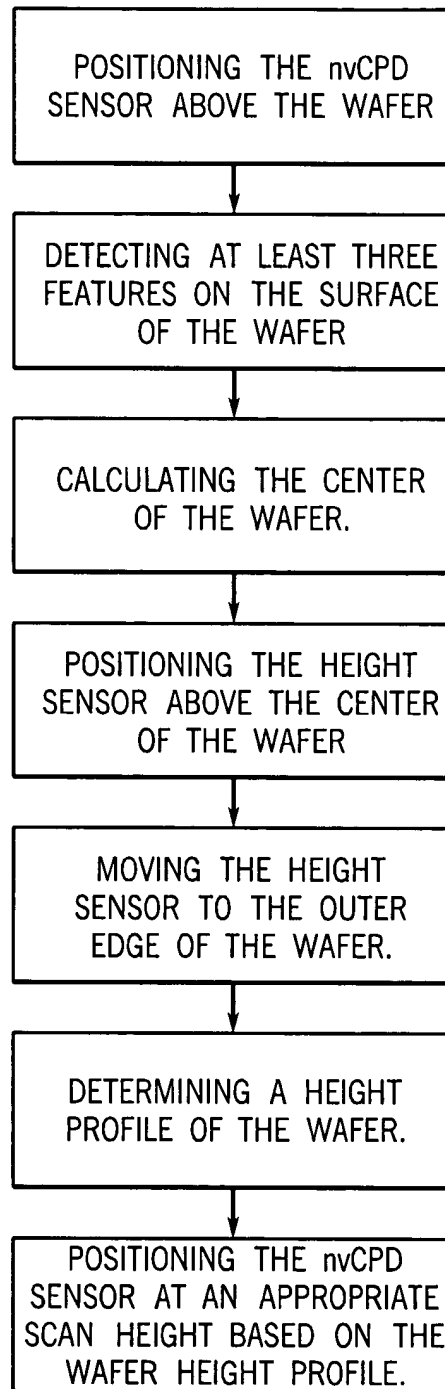


FIG. 18

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

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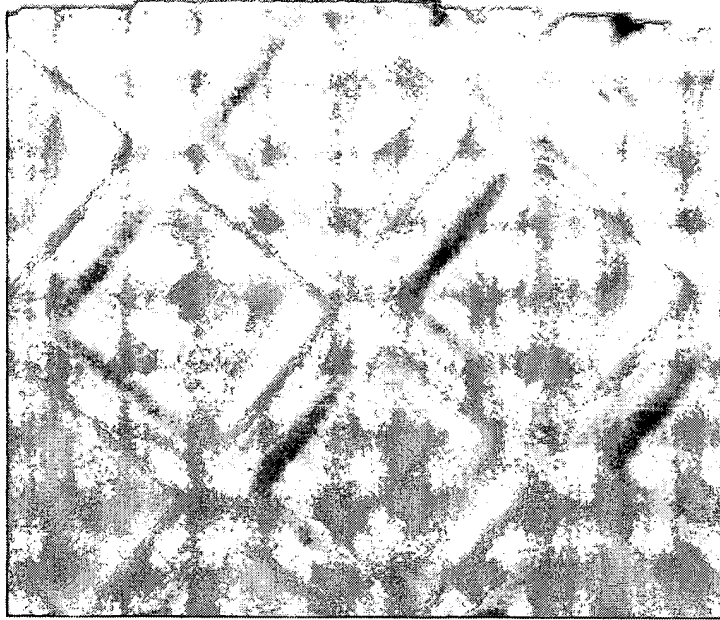


FIG. 19

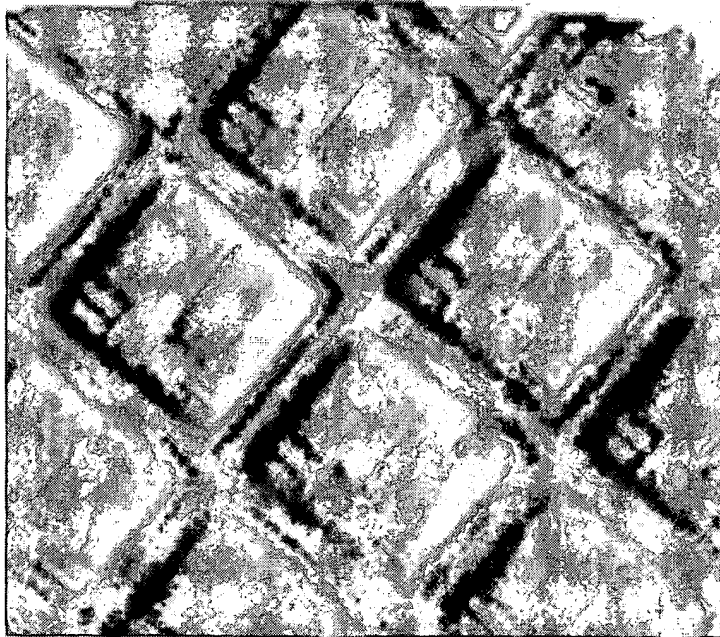


FIG. 20

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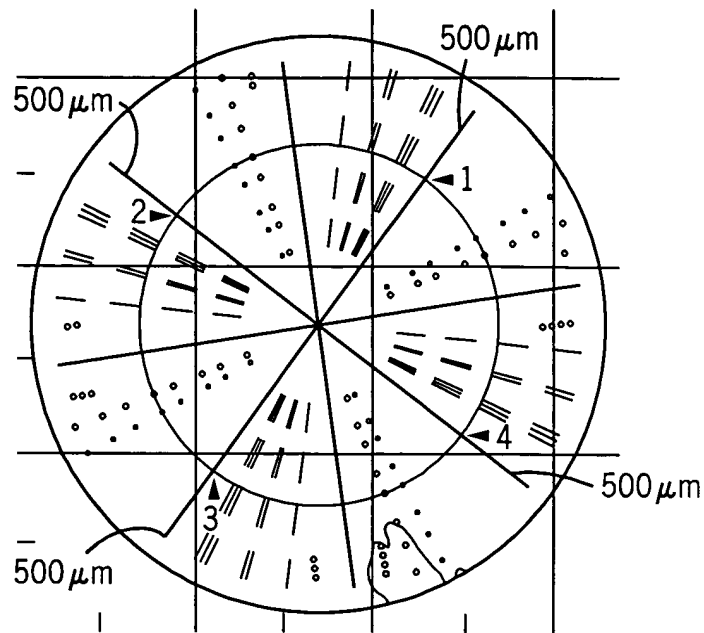


FIG. 21A

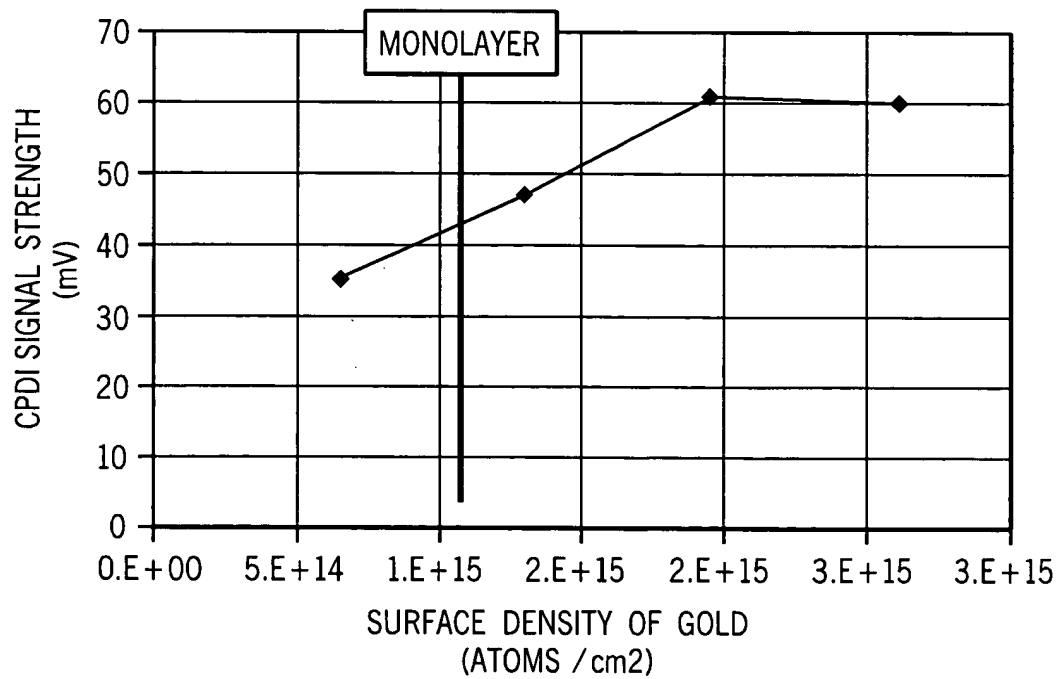


FIG. 21C

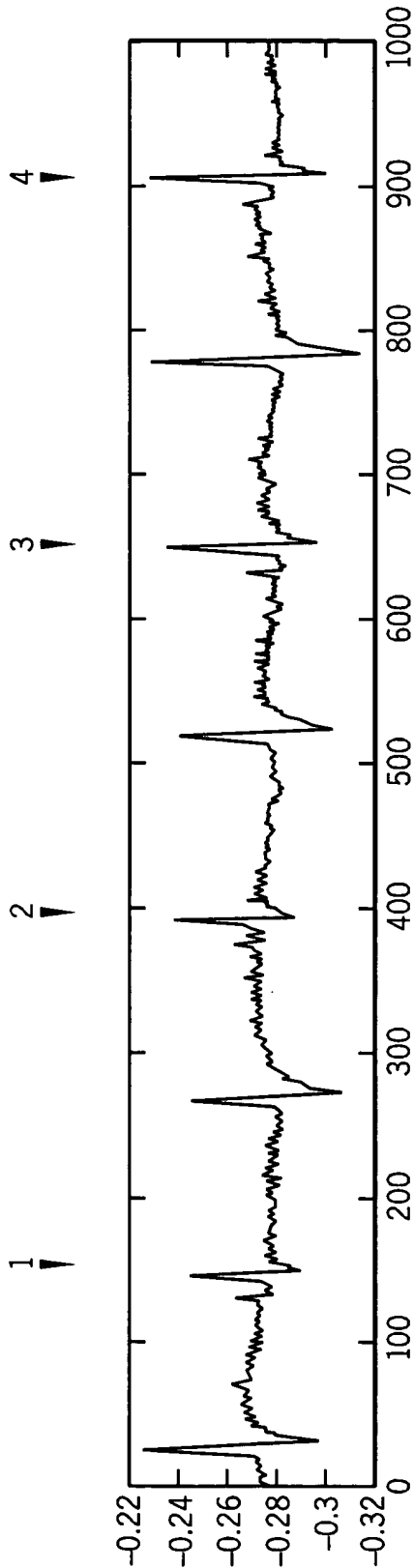


FIG. 21B

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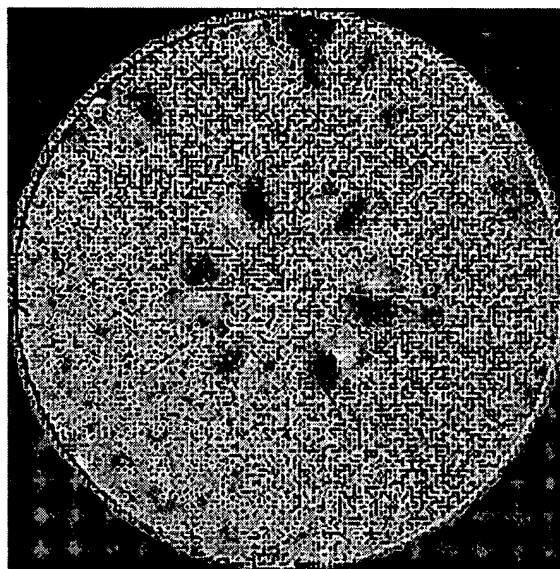


FIG. 22A

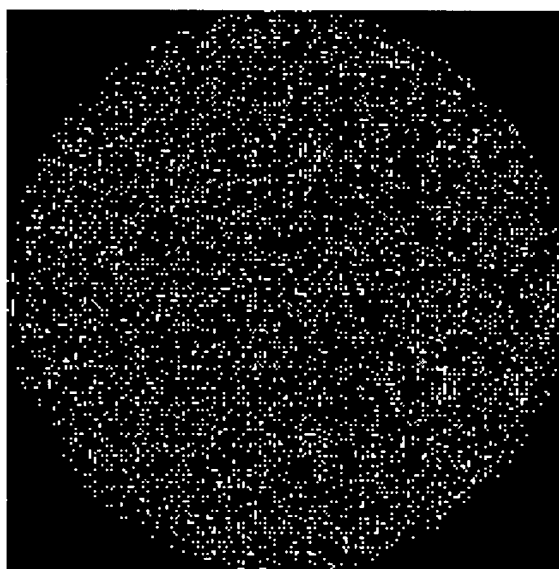


FIG. 22B

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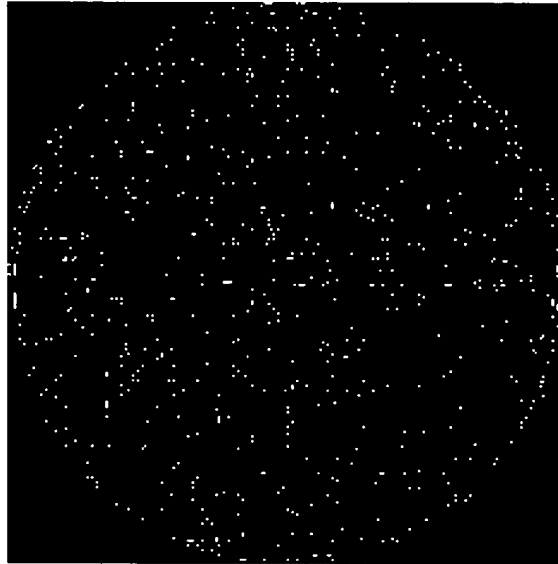


FIG. 22C

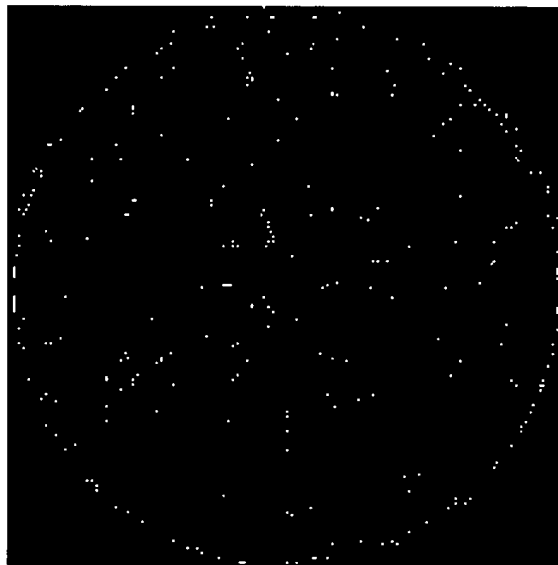


FIG. 22D

Title: WAFER INSPECTION SYSTEM

Inventor(s): Steele et al.

Appl. No.: 10/771,628

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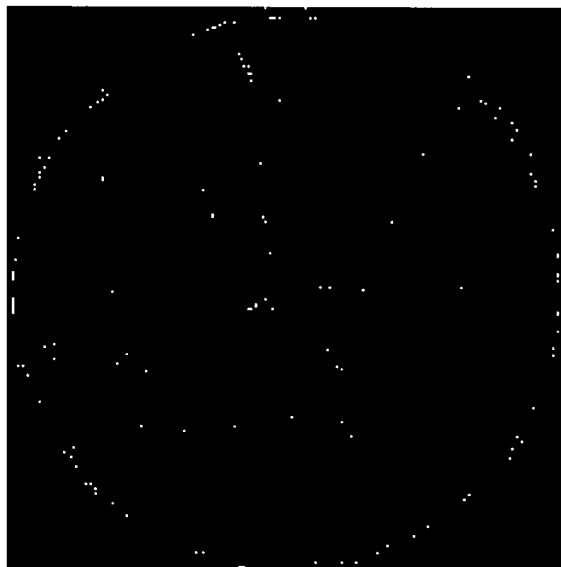


FIG. 22E

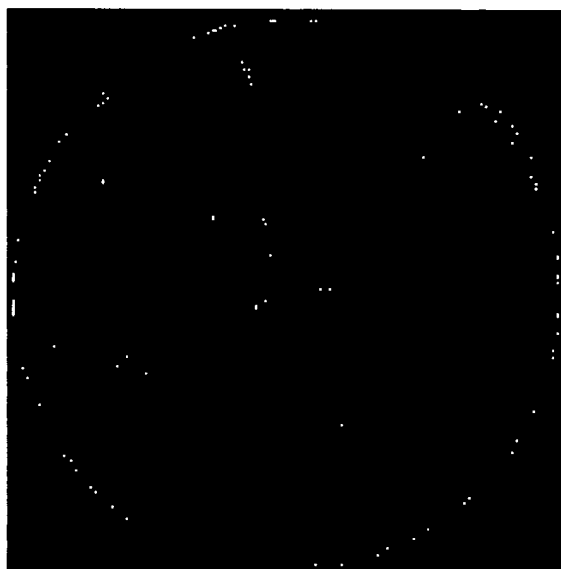


FIG. 22F

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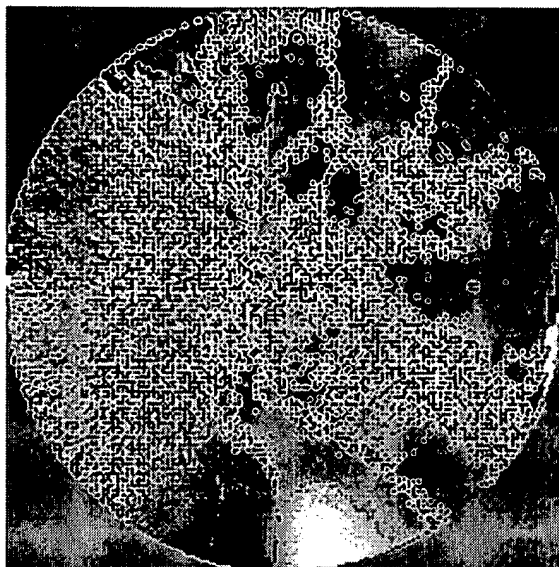


FIG. 23A

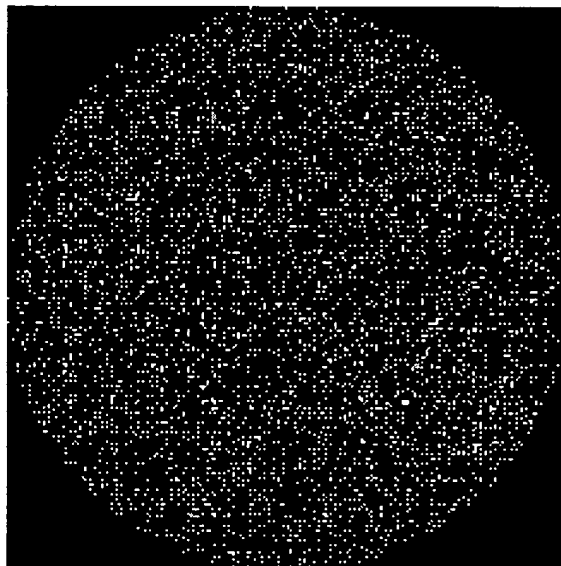


FIG. 23B

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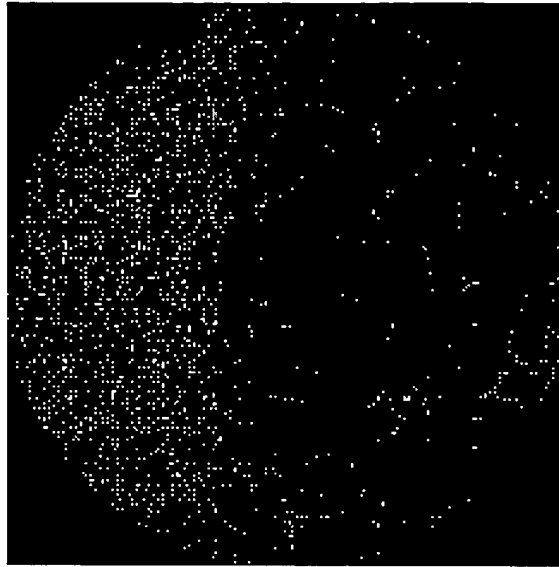


FIG. 23C

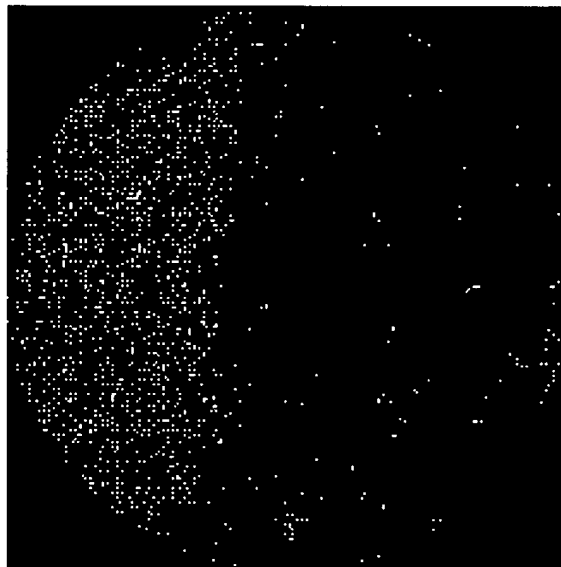


FIG. 23D

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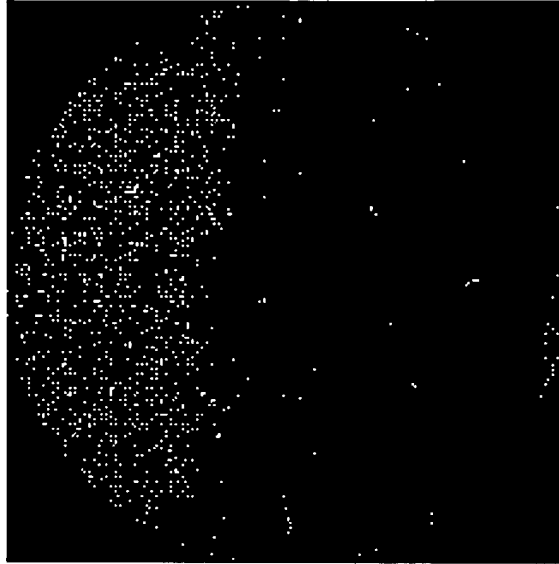


FIG. 23E

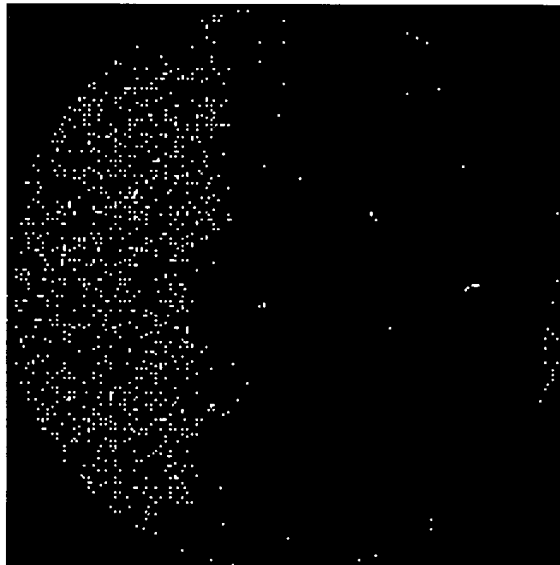


FIG. 23F

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